



Atomic structure of GaAs nanowires and InAs/GaAs graded interfaces in nanowires grown under VLS conditions The XXXIII Annual Meeting of the Electron Microscopy Society of India, Bangalore -2012

Johnson, Erik

Publication date:
2012

Document version
Early version, also known as pre-print

Citation for published version (APA):
Johnson, E. (2012, Jul 2). Atomic structure of GaAs nanowires and InAs/GaAs graded interfaces in nanowires grown under VLS conditions The XXXIII Annual Meeting of the Electron Microscopy Society of India, Bangalore - 2012.



The XXXIII Annual Meeting of the Electron Microscopy Society of India

2-4 July 2012

Satellite workshop 1st July and 5-6th July, 2012

**Jointly Organised by Indian Institute of
Science, Bangalore**

Chief Sponsors

EMSI 2012

Other Sponsors



The EMSI 2012 at Bangalore is fast approaching. We have attempted to incorporate many novel features in the organisation of this Year's EMSI. These include organisation of several satellite workshops with limited participation to impart training to the users of the microscopes in advanced techniques before or after the three day event. There are no additional charge for availing these opportunity. The details are given at the end of this circular. In addition there will be on display new products and live demonstration to the interested users throughout the period of the conference. This will bring our society meeting in line with the meetings of active microscope societies in other countries. We are delighted to have the presence of the president of the International Microscope Society in our midst. We have a very impressive list of plenary lecturer which will benefit the members of our society. In addition we shall have talks where latest advancement in this field will be presented by the leaders of the instrument manufacturer.

We like you to participate actively in large numbers. Please register/submit your abstracts via the website www.afmm.iisc.ernet.in/emsi2012. Details of hotels are also posted on the website. Kindly contact the hotels directly for reservations. However, we have very special rates consistent with the Indian Government rates at Sheraton on single and double occupancy basis. In case you like to avail this, you can e mail directly to us or to sachin.gudodagi@sheraton.com

Sheraton, Bangalore Rates

| | |
|------------------------------|-----------------------|
| Single occupancy | 6500 inclusive of tax |
| Double occupancy | 7500 inclusive of tax |
| Single occupancy (pool view) | 7000 + 20.30% tax |
| Double occupancy (pool view) | 8000 + 20.30 %tax |



Registration Fee

| | |
|-------------------------------------|------------------------|
| <i>EMSI Members</i> | <i>INR 3,000</i> |
| <i>Non-Members</i> | <i>INR 5,000</i> |
| <i>Foreign Delegates (Spouse)</i> | <i>US \$ 400 (250)</i> |
| <i>Student Members</i> | <i>INR 1,000</i> |
| <i>Student Non-members</i> | <i>INR 2,000</i> |
| <i>Company Registration</i> | <i>INR 18,000</i> |
| <i>Spouse / Accompanying Person</i> | <i>INR 2,000</i> |

Following are the confirmed plenary and invited speakers to date.

Confirmed Plenary Speakers

1. C. Barry Carter, University of Connecticut, USA
2. Gustaaf van Tendeloo, University of Antwerp, Belgium
3. Andreas Rosenauer, University of Bremen, Germany
4. Rajarshi Banerjee, University of North Texas, USA
5. F.M. Ross, IBM, USA
6. Atanu Basu, National Institute of Virology, India
7. Krishanu Ray, Tata Institute of Fundamental Research, India
8. Amar Nath Ghosh, NICED
9. P.M. Ajayan, Rice University, USA
10. Eiji Abe, University of Tokyo, Japan
11. Angus Kirkland, Oxford University, UK
12. J. Mayer, Ernst Ruska Centre for Microscopy, Juelich, Germany
13. Rafal Dunin-Borkowski, Ernst Ruska Centre for Microscopy, Juelich, Germany
14. Erik Johnson, Niels Bohr Institute, Denmark
15. D.D. Sarma, IISc, India

Confirmed Invited Speakers

1. M. Vijayalakshmi, IGCAR, India
2. Anna Ceguerra, Univ. Sydney, Australia
3. K. Muraleedharan, DMRL, India
4. Dinesh Srivastava, BARC, India
5. Sarah Haigh, Univ. Manchester, UK
6. Knut Muller, Univ. Bremen, Germany
7. Yaron Kaufmann, Technion, Israel
8. P.V. Satyam, Institute of Physics, India
9. A.K. Srivastava, NPL, India

10. Alok Singh, NIMS, Japan
11. Krishanu Biswas, IITK
12. Partha Ghoshal, DMRL
13. Balamuralikrishnan, DMRL
14. Asim Tewari, IITB
15. Somnath Bhattacharya, TIFR
16. Balaji Jagirdar, IISc
17. G.V.S. Sastry, BHU
18. B.S. Murty, IITM
19. R. Gopalan, ARCI
20. Dheepa Srinivasan, GE
21. R. Tewari, BARC
22. Sundararaman, UoHyd
23. A.N. Ghosh, NICED
24. R. Natesh, IISER Pune
25. S. Ghaskadbi, MACS
26. R.P. Tandon, Univ. Delhi
27. Kaiser Jamil

We hope to have a stimulating week learning about the latest advances in microscopy and we hope you will be able to participate and contribute to the success of the proceedings. Hoping to see you in Bangalore

Our contact Address:

Prof. N. Ravishankar

Convener, EMSI 2012

Phone: (91) 80 22933255

Fax : (91) 80 23607316

E mail: iiscemsi@gmail.com

emsi2012@afmm.iisc.ernet.in

URL: <http://afmm.iisc.ernet.in/emsi2012>

Organising Committee

EMSI2012

Satellite Workshops

1. NRCM IISc – Hysitron Workshop on In-situ Microscopy Techniques, 1st July 2012

Lectures in the morning and hand-on/demonstrations in the afternoon. Led by F.M.Ross of IBM, a leading expert in In Situ Microscopy, the talks in the morning will cover In Situ studies using the advanced holders for heating and mechanical property studies. There will be 2 talks by in the morning sessions followed by demo/hands-on session in the afternoon. The latest development on In Situ microscopy techniques will be discussed in this workshop. A limited number of supports for interested University/college teachers covering travel and stay are available.

For Registration please mail to ugc@materials.iisc.ernet.in

2. Demo/tutorial sessions by Gatan Inc., 1st July 2012

1) Digital Micrograph (GMS) s/w introduction , tips for calibration optimization of acquisition , capture and manipulation of image & data from Gatan CCD Camera. Digital Streaming Video acquisition and tips.

2) Tensile Test module (MTEST) hardware and software introduction plus tips for use and optimization of data collection.

These will be conducted (in batches in approximately in 60 min time frame) , on the equipments at Advanced Facility for Microscopy and Microanalysis, IISc

For Registration please mail to vdattu@gatan.com

In addition to the demo/tutorial on 1st July, please visit Gatan Booth, during the conference for demo/hands-on training /tips on use of Digital Micrograph software and tensile software use.

3. Zeiss Workshop on Correlative Microscopy 1st July, 2012

Zeiss will conduct a demonstration session on correlative microscopy. Details will be posted on the Zeiss website soon.

4. Workshop & Hands-on Experience on JEOL Electron Optics Products, 5-6 July, 2012

JEOL, a Japanese major in the field of Electron Microscopy is pleased to announce a 2-day Workshop and hands-on experience on JEOL electron optics products on July 5th and 6th, 2012 in IISc Bangalore as a continuation to the EMSI meeting. During the workshop, there will be experts from JEOL who will demonstrate JEOL 200 kV FEGTEM, JEOL EPMA and JEOL InTouchScope SEM with EDS.

For registrations, please mail to jeolworkshop@jeolindia.com

5. Workshop on Quantitative Analysis aspects of EDS system when used with SEM and TEM by Oxford Instrument, 5th July, 2012

Oxford Instruments will conduct a theory presentation followed by demonstration of EDS on FEI FESEM and JEOL TEM on 5th July 2012 .

For registration, please contact at Oxford Instrument Exhibition stall during the conference time.

6. FEI will conduct demonstration on TEM

For registration, please contact at FEI (ICON Analytical) Exhibition stall during the conference time.